N-Ch MOSFET

General Description

The WSD40120DN56G use advanced SGT MOSFET technology to provide low $R_{\rm DS(ON)}$, low gate charge, fast switching and excellent avalanche characteristics.

This device is specially designed to get better ruggedness and suitable

Features

- Low R_{DS(on)} & FOM
- Extremely low switching loss
- Excellent stability and uniformity or Invertors

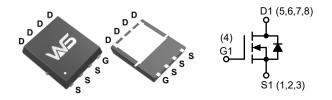
Product Summery

BV _{DSS}	R _{DSON}	l _D
40V	$1.4 m\Omega$	120A

Applications

- Consumer electronic power supply
- Synchronous-rectification
- Synchronous-rectification applications

DFN5X6-8L Pin Configuration



Absolute Maximum Ratings at T_J=25 ℃ unless otherwise noted

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	40	V
V_{GS}	Gate-Source Voltage	±20	V
I _D @T _C =25℃	Continuous Drain Current, V _{GS} @ 10V ¹	120	Α
I _D @T _C =100℃	Continuous Drain Current, V _{GS} @ 10V ¹	82	А
I _{DM}	Pulsed Drain Current ²	400	А
EAS	EAS Single Pulse Avalanche Energy ³		mJ
I _{AS}	Avalanche Current	40	А
P _D @T _C =25°C	P _D @T _C =25 ℃ Total Power Dissipation ⁴		W
T _{STG}	T _{STG} Storage Temperature Range		$^{\circ}$
TJ	Operating Junction Temperature Range	-55 to 150	$^{\circ}$

Thermal Data

Symbol	Parameter	Тур.	Max.	Unit
$R_{ heta JA}$	Thermal Resistance Junction-Ambient ¹		50	°C/W
$R_{ heta JC}$	R _{θJC} Thermal Resistance Junction-Case ¹		1.0	°C/W

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Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	40			V
$\triangle BV_{DSS}/\triangle T_{J}$	BV _{DSS} Temperature Coefficient	Reference to 25℃ , I _D =1mA		0.043		V/°C
R _{DS(ON)}	Static Drain-Source On-Resistance ²	V _{GS} =10V , I _D =20A		1.4	1.8	mΩ
R _{DS(ON)}	Static Drain-Source On-Resistance ²	V _{GS} =4.5V , I _D =20A		2.0	2.6	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	-V _{GS} =V _{DS} , I _D =250uA	1.2	1.6	2.2	V
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	VGS-VDS, ID -250UA		-6.94		mV/℃
l	Drain-Source Leakage Current	V _{DS} =32V , V _{GS} =0V , T _J =25℃			1	uA
I _{DSS}	Diam-Source Leakage Current	V _{DS} =32V , V _{GS} =0V , T _J =55℃			5	uA
I _{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 20V$, $V_{DS}=0V$			±100	nA
gfs	Forward Transconductance	V _{DS} =5V , I _D =20A		53		S
R_g	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		1.0		Ω
Q_g	Total Gate Charge (10V)			45		
Q _{gs}	Gate-Source Charge	V _{DS} =15V , V _{GS} =10V , I _D =20A		12		nC
Q_{gd}	Gate-Drain Charge			18.5		
T _{d(on)}	Turn-On Delay Time			9		
Tr	Rise Time	V_{DD} =15V , V_{GEN} =10V , R_{G} =3.3		18.5		200
T _{d(off)}	Turn-Off Delay Time	Ω , I _D =20A ,RL=15 Ω .		32		ns
T _f	Fall Time			58.5		
C _{iss}	Input Capacitance			3972		
C _{oss}	Output Capacitance	V _{DS} =20V , V _{GS} =0V , f=1MHz		1119		pF
C _{rss}	Reverse Transfer Capacitance	7		82		

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
I _S	Continuous Source Current	V _G =V _D =0V , Force Current			100	Α
V _{SD}	Diode Forward Voltage ²	V _{GS} =0V , I _S =1A , T _J =25℃			1.2	V

Note:

- 1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2 .The data tested by pulsed , pulse width $\leq 300 \text{us}$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is VDD=25V,VGS=10V,L=0.5mH,IAS=40A 4.The power dissipation is limited by 150 $^{\circ}$ C junction temperature
- 5 .The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.



Typical Characteristics

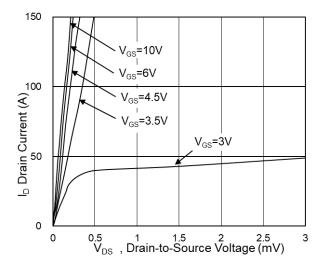


Fig.1 Typical Output Characteristics

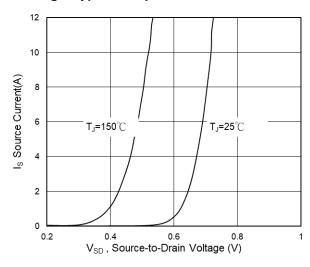


Fig.3 Source Drain Forward Characteristics

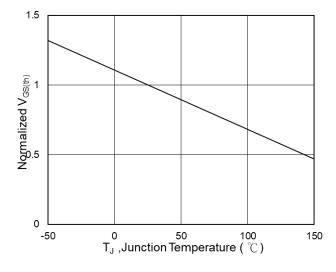


Fig.5 Normalized V_{GS(th)} vs T_J

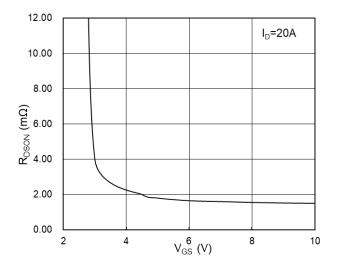


Fig.2 On-Resistance vs G-S Voltage

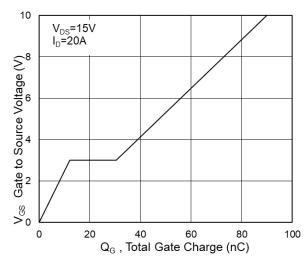


Fig.4 Gate-Charge Characteristics

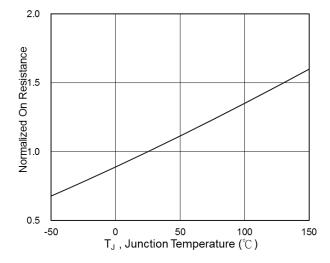
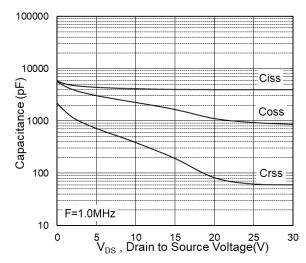


Fig.6 Normalized R_{DSON} vs T_J





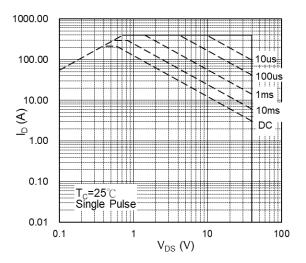


Fig.7 Capacitance

Fig.8 Safe Operating Area

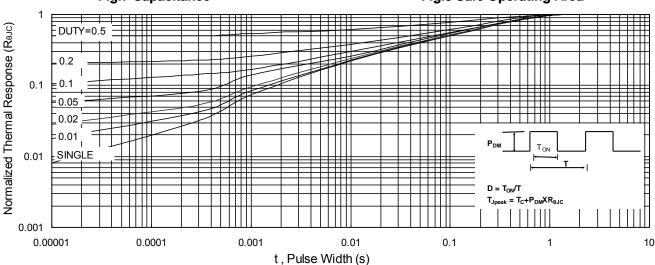
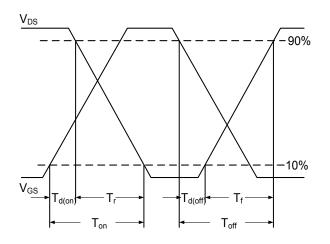


Fig.9 Normalized Maximum Transient Thermal Impedance



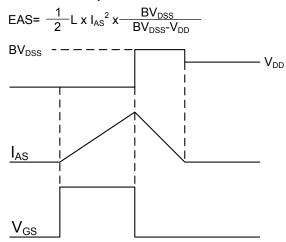
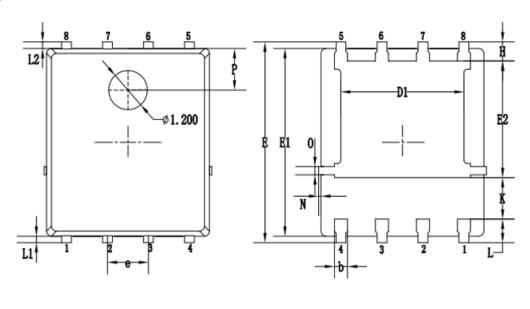
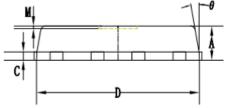


Fig.10 Switching Time Waveform

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Packaging information





CVMDOLC	MILLIMETERS				
SYMBOLS	MIN.	NOM.	MAX.		
Α	0.90	1.05	1.20		
b	0.35	0.40	0.50		
С	0.20	0.25	0.35		
D	4.90	5.05	5.20		
D1	3.72	3.82	3.92		
E	6.00	6.15	6.30		
E1	5.60	5.75	5.90		
E2	3.47	3.57	3.67		
е		1.27 BSC.			
Н	0.48	0.58	0.68		
K	1.17	1.27	1.37		
L	0.64	0.64 0.74			
L1/L2		0.20 REF.			
θ	8°	10°	12°		
М		0.08 REF.			
N	0	-	0.15		
0		0.25 REF.			
Р		1.28 REF.			



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